

<b>Notice of References Cited</b>	Application/Control No. 10/576,317		Applicant(s)/Patent Under Reexamination CHAPMAN ET AL.	
	Examiner Yuan L. Chen		Art Unit 4193	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0081095	05-2003	Yi et al.	347/101
*	B	US-2002/0154187	10-2002	Wong et al.	347/17
*	C	US-4,999,646	03-1991	Trask, Jeffrey L.	347/41
*	D	US-6,742,884	06-2004	Wong et al.	347/99
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	2030929	07-1979	GB	Clinton et al.	B41C 1/02
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.